

<b>Notice of References Cited</b>	Application/Control No. 10/693,872	Applicant(s)/Patent Under Reexamination HAYAMA, AKIRA	
	Examiner Mariceli Santiago	Art Unit 2879	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0113540	06-2004	Niibori et al.	313/495
	B	US-			
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	L	US-			
	M	US-			

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